

Search Notes

Application/Control No.

10/633,530

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

SAITO ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22,23,29 30,33	6/22/2005	SWH
417	477.1	6/22/2005	SWH
417	477.7	6/22/2005	SWH
417	477.8	6/2/2005	SWH
417	477.11	6/22/2005	SWH
417	476	6/2/2005	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Primary Charles Freay (AU 3746).	6/21/2005	SWH